

# ECSE 331: Electronics

## Laboratory Report

### Laboratory Experiment#5

MOSFETs And BJTs DC Characteristics

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Submitted:

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# Laboratory Experiment#5

## MOSFETs and BJT DC Characteristics

**Abstract**— The purpose of laboratory experiment number five, was to explore the functions and characteristics of MOSFETs and BJTs. In the first part of this laboratory, the I-V characteristics of the MOSFET was found and drawn for different gate voltages, then the transconductance  $g_m$  of the circuit was found. Then in the second part, the behavior of the MOSFET was studied at various temperatures. Then the same experiment was conducted on the BJT transistor: The I-V curve was drawn at various gate voltages, then the transconductance for the BJT was found and finally, the behavior of the BJT was studied at various temperatures. Experimental results showed that as the temperature of the transistors increased,  $I_{DS}$  also increased. So as the temperature increased the current conducted increased. In the introduction, the results will be discussed further.

### I. INTRODUCTION

The goal of this laboratory was to test, and explore the behavior of the different transistors, draw their I-V diagrams using the NI Elvis-II test instrument. More specifically, the I-V curve for the MOSFET and BJT transistors were drawn using the data taken with the NI Elvis instrument. Then a resistor network was designed to find the DC operating point of the transistors. Finally, the effect of temperature on the operation of the transistors was tested and found. In the main body of this lab report the results for each of the circuits analyzed will be presented in a clear and concise manner.

### II. MAIN BODY

We conducted several experiments with two kinds of transistors: The MOSFET and BJT. Their I-V curves were traced and the effects of temperature on their behaviors were found.

#### A. MOSFET $i_D$ - $v_{DS}$ Characteristics Using Curve Tracer

#### B. MOSFET Temperature Effects

#### C. BJT $i_D$ - $v_{DS}$ Characteristics Using Curve Tracer

#### D. BJT Temperature Effects

#### A. MOSFET $i_D$ - $v_{DS}$ Characteristics Using Curve Tracer

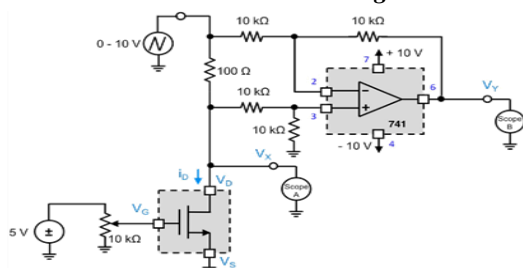


Fig1. Circuit diagram for I-V characteristic used in part A

I. The circuit diagram in figure 1 was constructed to measure  $V_{DS}$  and  $I_D$  and trace the I-V curve. This experiment was repeated multiple times with different gate voltages  $V_g$ . A sawtooth waveform going from 1V-10V was applied.

$V_{in}$	$V_x = V_D$	$I_D = V_y / -100$
0.5	510mV	0.29mA
1.5	1030mV	1.89mA
2.5	1050mV	4.74mA
2.7	1059mV	5.04mA
2.9	1059mV	5.20mA
2.95	1059mV	5.46mA
3	1059mV	5.46mA
3.5	1059mV	5.46mA
4	1059mV	5.46mA

Table 1:  $V_{DS}$  and  $I_D$  as a function of  $V_{in}$  when  $V_g=0$

From the table 1, it can be seen that  $I_D$  is very small, close to around 0.29mA when  $V_D$  was around 510mA, but as the voltage at the drain was increased, the current increased to around 5.46mA, where it saturated. Ideally it should be 0, but very rarely, circuits and elements act as ideal elements.

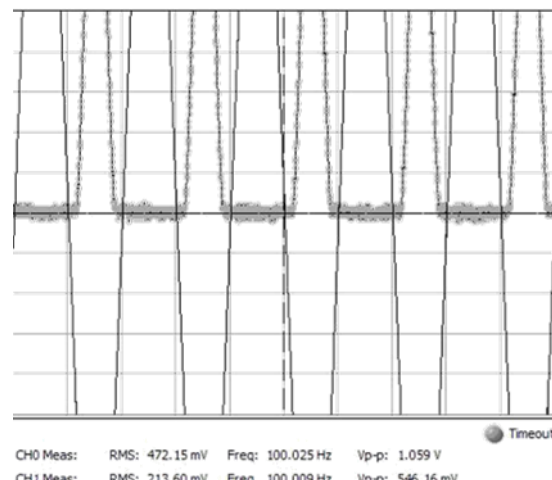


Fig2. Oscilloscope measurement when gate  $v=0V$  and  $V_{in}=3.5V$

II. On the same circuit as in part I, the gate voltage  $V_g$  was increased to 1V, and the data collected, then  $V_g$  was increased to 2V and so on until the gate voltage had reached 5V, for each case 1-5V gate voltage the I-V curve was constructed

using the data collected with the Oscilloscope. Below are the table of  $I_{DS}$  and  $V_D$  as  $V_{in}$  was varied.

$V_{in}$	$V_x=V_D$	$I_D= v_y/-100$
0.5	502mV	0.29mA
1.5	1030mV	1.89mA
2.5	1050mV	4.74mA
2.6	1059mV	5.04mA
2.65	1059mV	5.20mA
2.7	1059mV	5.46mA
2.8	1059mV	5.46mA
3	1059mV	5.46mA
3.2	1059mV	5.46mA
3.5	1059mV	5.46mA

Table 2 for  $V_D$  vs  $I_{DS}$  as  $V_{in}$  is varied for  $V_g= 1V$

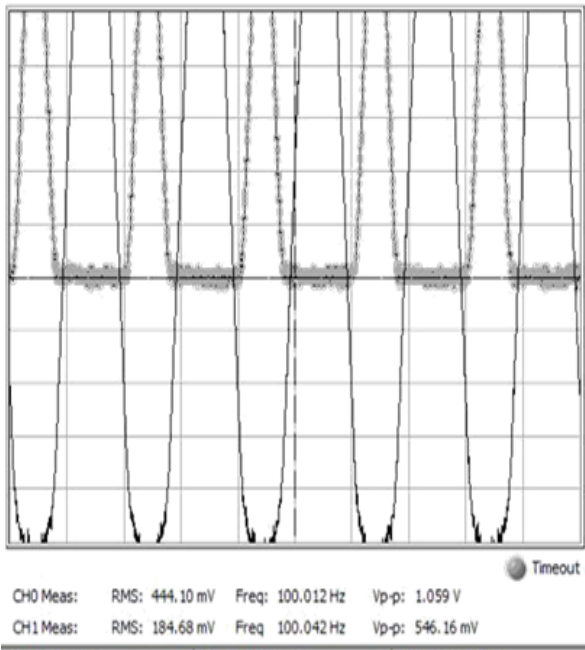


Fig3. Oscilloscope measurement when gate v=1V and  $V_{in}$ =2.8V

As we can see from the data in table 2,  $I_{DS}$  is around 0.29mA when the drain voltage is around 500mV, but as it increases, the current increase to a saturated value of about 5.46mA, just like the previous case where  $V_g=0v$ .Theoretically, the value should have been 0 because  $V_g$  was 1V and we know that  $T_{hreshold}=2v$ . For current to flow theoretically, we need to have a  $V_g$  larger than threshold.

When  $V_g$  is superior to 2V, we start to see the behavior of the MOSFET, if we plot the data of table 3, we see that the I-V curve in the first part consists of a linear function, where  $I_D$  increases as we increase  $V_{in}$ , then at a certain point, when  $V_{in}$  is more than 1.9V, so around the Threshold voltage,  $I_D$  saturates to a value of 7.05mA, as it can be seen in figure 4.

$V_{in}$	$V_x=V_D$	$I_D= v_y/-100$
0.5	162mV	2.47mA
0.75	265mV	3.44mA
1	380mV	4.32mA
1.7	664mV	6.55mA
1.8	664mV	6.89mA
1.85	668mV	7.01mA
1.9	670mV	7.05mA
2	680mV	7.05mA

Table 3 for  $V_D$  vs  $I_{DS}$  as  $V_{in}$  is varied for  $V_g= 2.5V$

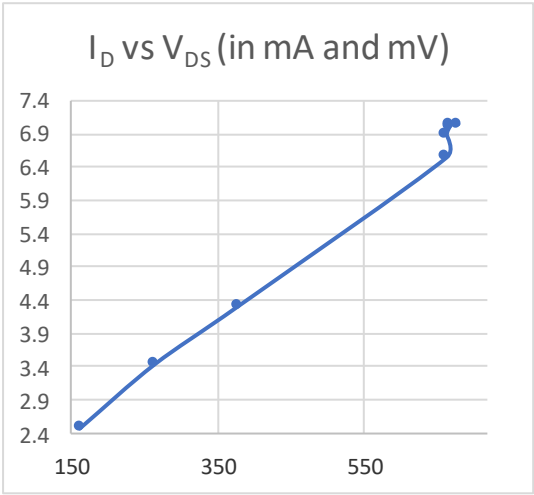


Figure 4: I-V curve when  $V_g=2.5V$

In table table 4,  $I_{DS}$  vs  $V_{DS}$  can be seen as  $V_{in}$  is varied. As it can be seen in its corresponding I-V curve in figure 5, the current increases linearly until  $V_{DS} = 116mV$  when  $V_{in}= 1.6V$ , then it saturates at current value of around 10.7mA.

$V_{in}$	$V_x=V_D$	$I_D= v_y/-100$
1	112mV	6.38mA
1.5	116mV	9.53mA
1.6	116mV	10.0mA
1.75	120mV	10.7mA
2	120mV	10.7mA
3	141mV	10.7mA
4	153mV	10.7mA
5	182mV	10.7mA

Table 4 for  $V_D$  vs  $I_{DS}$  as  $V_{in}$  is varied for  $V_g= 3.7v$

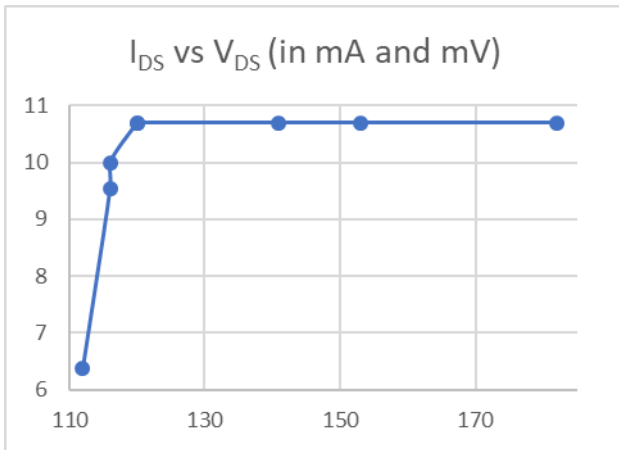


Figure 5: I-V curve when  $V_g=3.7V$

We can clearly see from the graph in figure 5 that the current saturates to a value of 10.7mA when  $V_D$  reaches a value of 116mV ( $V_{in}=1.85V$ ).

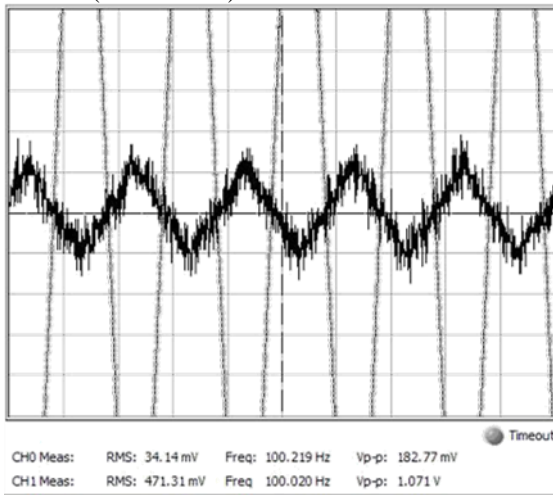


Fig6. Oscilloscope measurement when gate  $v=1V$  and  $V_{in}=2.8V$

Finally, in the table and graph below are the data and I-V curve for the MOSFET when gate voltage  $V_g=4.92V$ .

$V_{in}$	$V_x=V_D$	$I_D=V_y/-100$
0.5	85mV	3.25mA
1	95mV	6.45mA
2	110mV	12.9mA
3	120mV	19.5mA
4	140mV	25.8mA
5	149mV	32.2mA
6	155mV	38.6mA
7	170mV	45.0mA
8	186mV	51.28mA
9	195mV	57.64mA
10	210mV	64.42mA

Table 5 for  $V_D$  vs  $I_{DS}$  as  $V_{in}$  is varied for  $V_g=4.92v$

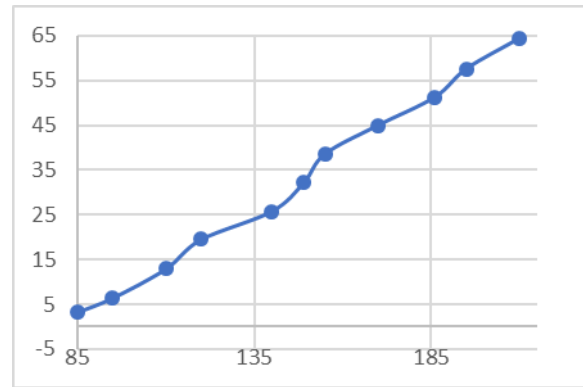
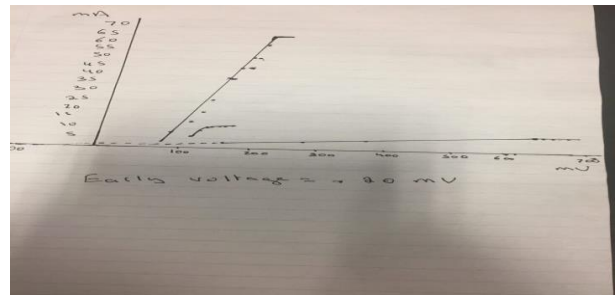


Figure 7: I-V curve when  $V_g=4.92V$

**III.** According to the Manufacturers data sheet, the threshold voltage is around 2V. We know that theoretically for current to flow in a linear way  $V_{DS} < V_{Gate} - V_{threshold}$ , so at the point  $V_{DS} = V_{Gate} - V_{threshold}$ , curve is no longer linear. From the graphs, we can easily find that point, and since we know  $V_{Gate}$ , for each I-V curve, we can find the Threshold voltage.

When  $V_g=2.5V$ , the saturation current is reached when  $V_{DS}=0.688V$ . Since we know  $V_{DS} = V_{Gate} - V_{Threshold}$ ,  $V_{Threshold} = 2.5 - 0.688v = 1.812V$ , which is very close to the value given by the data sheet. So the **Threshold voltage** found **experimentally** is **around 1.812V**.

**IV.** Figure 8 shows the combination of all the curve traces into a single plot, from it we get a general idea of its overall behavior. From the graph in figure 4 the Early voltage of our device was extrapolated **to be around 12V**.



Early voltage extrapolation

**V.** To find the transconductance  $g_m$ , of our device the following formula was used:  $g_m = \Delta I_D / \Delta V_{GS}$ .

Using the circuit in figure 1, the following data were measured.

$V_{g1}=3V$ ,  $i_{D1}=37.81mA/-100$ ,  $V_{g2}=3.1V$  and  $i_{D2}=33.61mA/-100$

$g_m = (((33.61-37.81)/-100) / 1000) / (0.1) = 0.42 \times 10^{-3}$

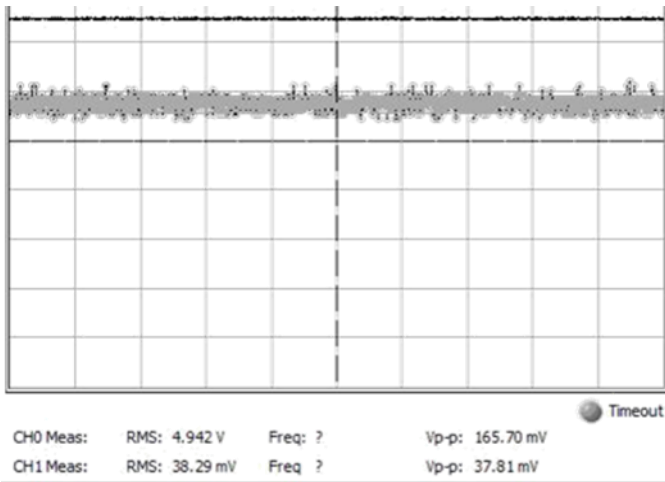


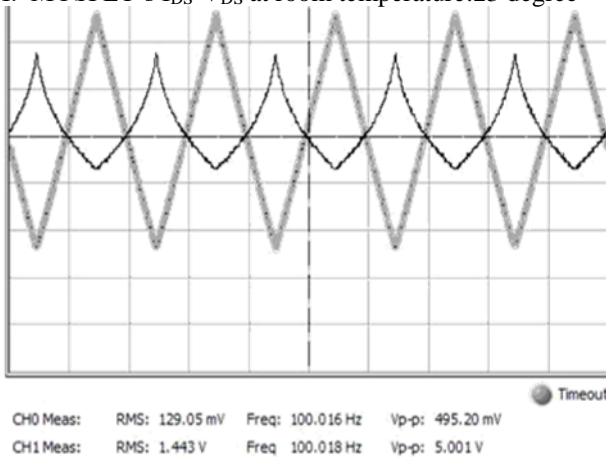
Fig6. Oscilloscope measurement when gate v=3 and  $V_y=37.81$

VI. Equivalent small signal model of MOSFET for low-frequency operation.

### B. MOSFET Temperature effects

The MOSFET's  $I_{DS}$ - $V_{DS}$  curve was measured using the circuit in figure 1 with the MOSFET being at different temperatures, theoretically for higher temperature there will be more holes and electrons at the interface of the metal gate and the substrate. Thus, a larger current can be conducted. Therefore, theoretically for higher temperatures the current conducted at a certain  $V_{DS}$  will be larger than for a lower temperature.

#### I. MOSFET's $I_{DS}$ - $V_{DS}$ at room temperature: 23 degree



$V_{DS}$  vs  $V_y$  for MOSFET at 23 degrees ( $V_{in}=8V$ )

Using the circuit in figure 1 with the MOSFET being at 23 degrees, we observe get the following data as written in table 6 and graph of  $I_{DS}$  vs  $V_{DS}$  figure 8.

$V_{in}$	$V_{DS}$	$I_{DS}$
1	54mV	6.42mA
2	100mV	12.76 mA
3	145 mV	18.90 mA
4	200 mV	21.41 mA
5	257 mV	31.79 mA
6	319 mV	37.70mA
7	400 mV	44.00 mA
8	495 mV	50.00 mA
9	660 mV	55.50 mA
10	949 mV	60.18 mA

Table 6.  $V_{DS}$  vs  $I_{DS}$  when at 23 degrees  $V_g=3v$

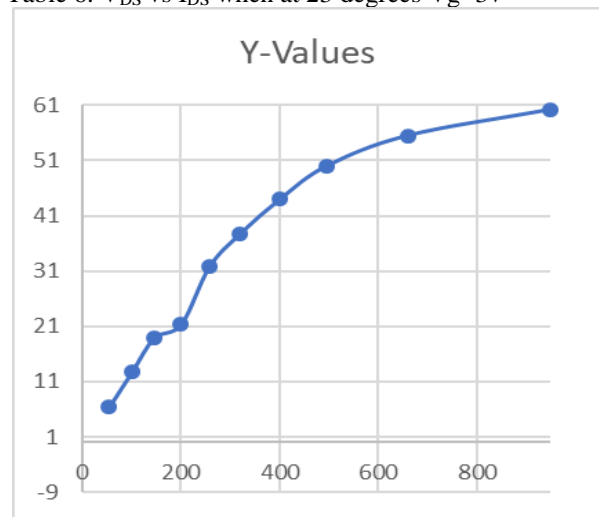


Fig3. I-V Characteristic at 23 degrees

#### II. MOSFET's $I_{DS}$ - $V_{DS}$ at -5 degrees:

Using the circuit in figure 1 with the MOSFET being at -5 degrees, we observe get the following data as written in table 7 and graph of  $I_{DS}$  vs  $V_{DS}$  figure 8.

$V_{in}$	$V_{DS}$	$I_{DS}$
1	83mV	6.20mA
2	170 mV	12.00 mA
3	270 mV	18.20mA
4	400 mV	24.10mA
5	660 mV	28.80 mA
6	1050 mV	33.00mA
7	1210 mV	36.87 mA
9	2460 mV	43.60 mA
10	2700 mV	49.00 mA

Table 7.  $V_{DS}$  vs  $I_{DS}$  when at -5 degrees  $V_g=3v$

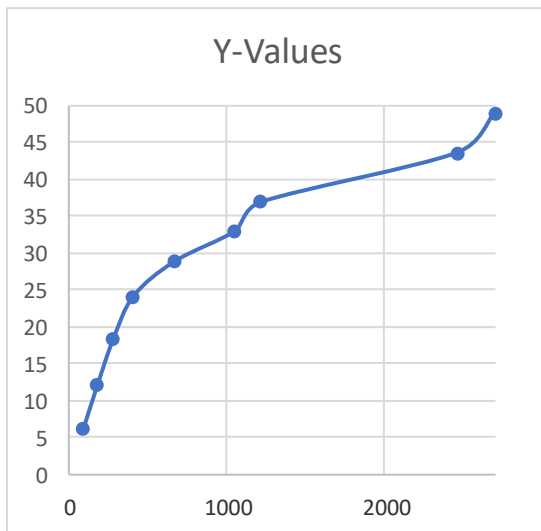
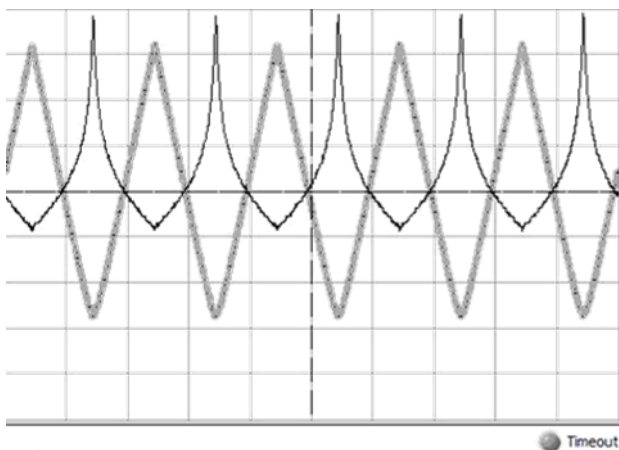


Fig4. I-V characteristic at -5 degrees C

### III. MOSFET's I-V curve at 60 degrees:



CH0 Meas: RMS: 206.35 mV Freq: 100.027 Hz Vp-p: 957.38 mV  
CH1 Meas: RMS: 1.784 V Freq: 100.032 Hz Vp-p: 5.976 V

$V_{DS}$  vs  $V_y$  for MOSFET at 60 degrees ( $V_{in}=10V$ )

Using the circuit in figure 1 with the MOSFET being at 60 degrees, we observe get the following data as written in table 8 and graph of  $I_{DS}$  vs  $V_{DS}$  figure 8.

$V_{in}$	$V_{DS}$	$I_{DS}$
1	49.00mV	6.42mA
2	95.5 0mV	12.70 mA
3	140.00 mV	19.00 mA
4	190.00 mV	25.40 mA
5	240.00 mV	31.79 mA
6	307.00 mV	37.70 mA
7	379.00 mV	42.65 mA
8	486.00 mV	50.10 mA
9	652.00 mV	55.20 mA
10	957.00 mV	60.10 mA

Table 8.  $V_{DS}$  vs  $I_{DS}$  when at -5 degrees  $V_g=3v$

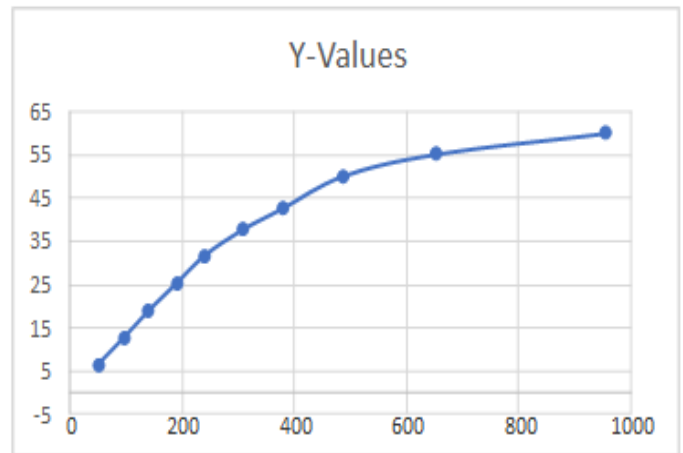


Fig5. I-V characteristics at 60 degree C

IV. As was explained earlier, from theory, we know that the MOSFETS behavior changes with temperature, as temperature increases the I-V curve shifts to the left, so the barrier voltage is lowered and when the temperature is decreased, the curve shift to the right, which means the barrier voltage is increased. This follows from the fact that as the temperature increases, we have more thermally generated holes and free electrons, this will decrease the voltage barrier at the PN junction. Which causes the MOSFET to conduct more current at lower voltages!

By comparing the three graphs, we see that for 23 degrees and 60 degrees the values and the graph are very similar, while for -5 degrees, for a given value of  $V_{DS}$ ,  $I_{DS}$  is smaller. That is explained by the fact that at lower temperatures, there are less free electrons and holes available to conduct current.

V. To reduce change in MOSFET behavior as a function of time, keep the devices temperature constant.

### C. BJT $I_{DS}$ - $V_{DS}$ Characteristics

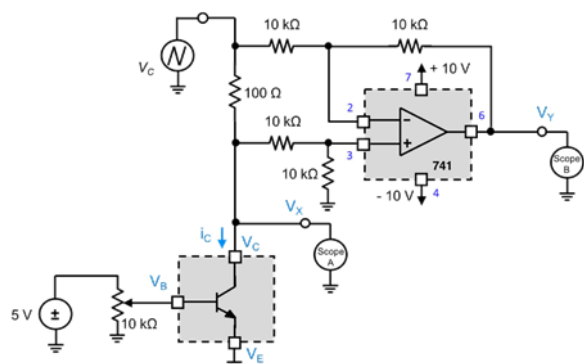


Fig6. Circuit diagram to find  $I_{DS}$  vs  $V_{DS}$  for the BJT

To analyze the behavior of I-V characteristic of the BJT, we build circuit in figure X and plot the curve for different values

of  $V_{in}$ . Similarly, to part A, our input signal is a sawtooth waveform that varies from 0 to 10v.

I. When the gate voltage is at 0, it is less than the threshold voltage needed to generate a current, so as a result  $I_{DS}$  is 0v irrespective of the  $V_{DS}$ .

$V_{in}$	$V_{DS}$	$I_{DS}$
1	0	0
.....	0	0
10	0	0

Table 9. BJT when  $V_g=0v$

When the gate voltage is at 0.2V, we start to get some current in the channel.

$V_{DS}$	$I_{DS}$
2v	0.077mA
3v	0.12 mA
6.98v	0.28 mA
7.96v	0.28 mA
9.42v	0.33mA

Table 10. BJT when  $V_g=0.2v$

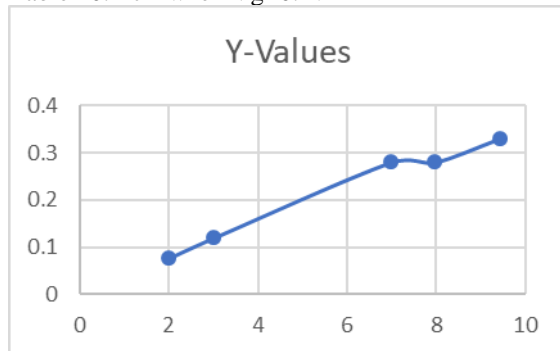


Fig7. Ids vs Vds when  $V_g=0.2v$

When  $V_g=0.4v$

Vin for BJT $v_g=0.4V$	Vd	Ids (mv)
	3.89v	0.077mA
	6.98v	0.245 mA
	7.96v	0.245 mA

Table 11. BJT When  $V_g=0.4v$

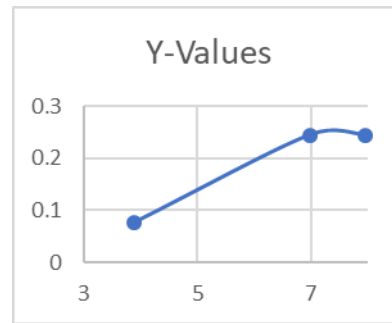


Fig 8. Ids vs Vds when  $V_g=0.4v$

When  $V_g=0.65v$

Vin for BJT $v_g=0.65V$	Vd	Ids (mv)
	2.26v	1.12mA
	5v	1.25 mA
	6.33v	1.33 mA
	7.96v	1.37 mA

Table 12. BJT When  $V_g=0.65V$

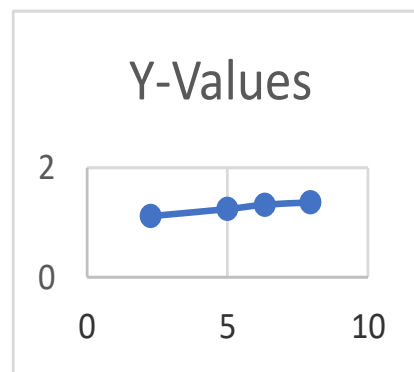


Fig 9. Ids vs Vds when  $V_g=0.65v$

When  $V_g=0.71v$

$V_{DS}$	$I_{DS}$
2.1	3.06mA
3.56	3.10mA
4.7	2.97 mA
6.49	3.23 mA
7.63	3.14 mA
8.77	3.26 mA

Table 13 BJT When  $V_g=0.71V$



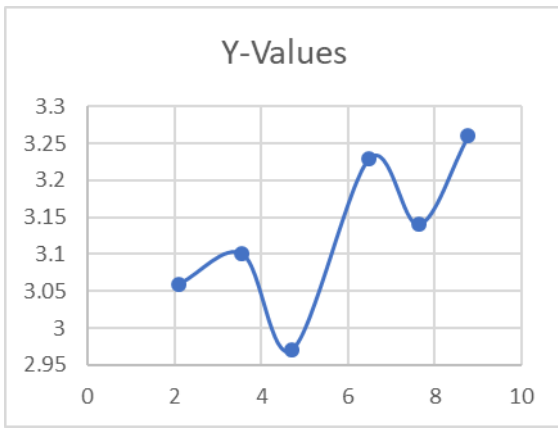


Fig 10. Ids vs Vds when Vg=0.71v

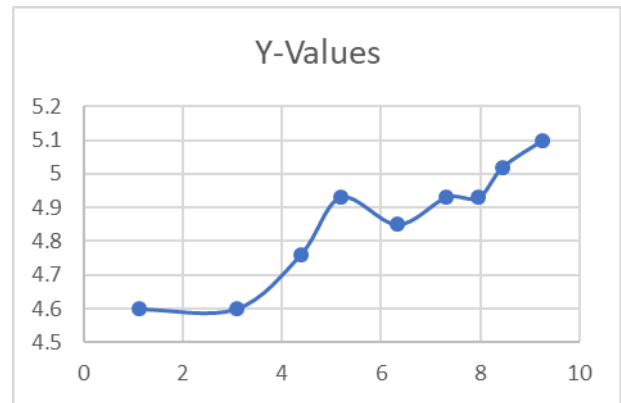
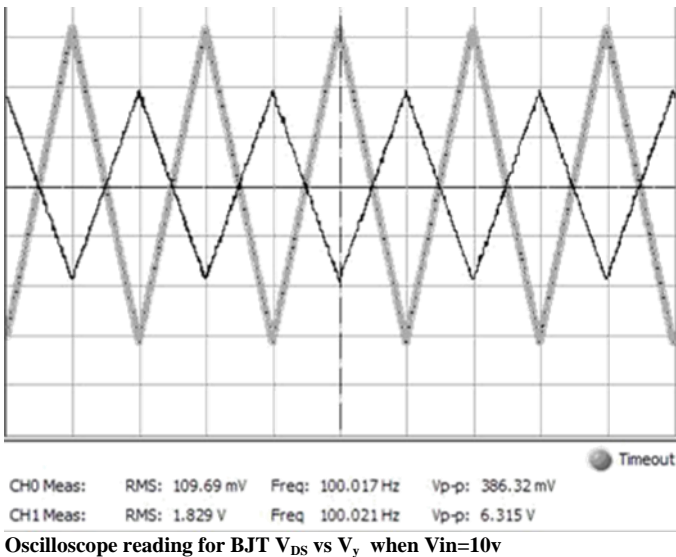


Fig 11. Ids vs Vds when Vg=0.75v



Oscilloscope reading for BJT  $V_{DS}$  vs  $V_y$  when  $V_{in}=10v$

When  $V_g = 0.75v$

$V_{DS}$	$I_{DS}$
1.12	4.60 mA
3.08	4.60 mA
4.38	4.76 mA
5.19	4.93 mA
6.33	4.85 mA
7.31	4.93 mA
7.96	4.93 mA
8.45	5.02mA
9.26	5.1mA

Table 14 BJT when  $V_g=0.75$

II. As it can be seen from the graphs and tables, at low gate voltages, the value of  $I_{DS}$  is very small, in the range of around 0.077mA to around 1.37mA. When the gate voltage is increased to around 0.71V, we see that the current starts to increase to around 3.26mA. Finally, for a gate voltage of 0.75, we see that the current  $I_{DS}$  goes from 4.6mA to up to 5mA for values of  $V_{DS}$  going from 1.12v to 8.45v.

III. The early voltage was extrapolated to be around 15 volts using the multiple graphs from figures 7-10.

IV. Computing the Transconductance of the device.

$$G_m = ((125.3 - 293) / 100) / (4.71 - 4.81) / 1000 = 0.168.$$

VI. Small signal model of BJT at low frequency:

#### D. Temperature Effect on I-V curve of BJT

Using the same circuit diagram, the I-V curve of the BTJ was measured at various temperatures. Theoretically, at lower temperatures the current  $I_{ds}$  is going to be lower and vice versa.



**I. I-V curve when BJT temperature is 22 degrees**  
Graph of I-V characteristic is in figure 10.

$V_{DS}$	$I_{DS}$
2.1	3.06mA
3.56	3.10mA
4.7	2.97 mA
6.49	3.23 mA
7.63	3.14 mA
8.77	3.26 mA

Table 15  $I_{DS}$  and  $V_{DS}$  for BJT when at 22 degrees

**II. When BJT temperature is -14 degree Celsius**

$V_{DS}$ in v	$I_{DS}$ in mA
0.797	0.077
2.43	0.035
4.22	0.161
5.03	0.202
5.68	0.282
6.49	0.246
8.45	0.287
9.10	0.311
9.91	0.287

Table 16  $I_{DS}$  and  $V_{DS}$  for BJT when at -14 degrees

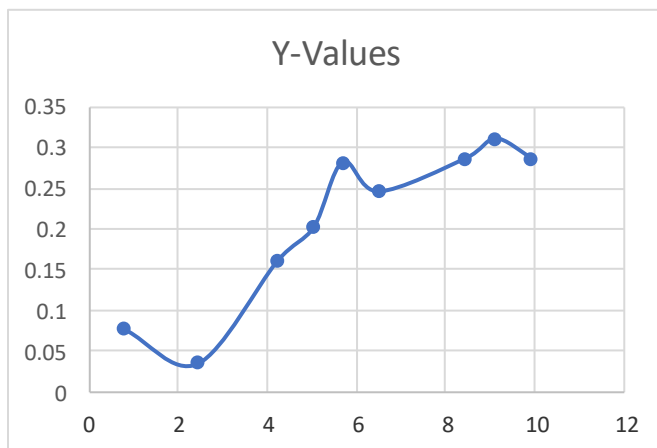
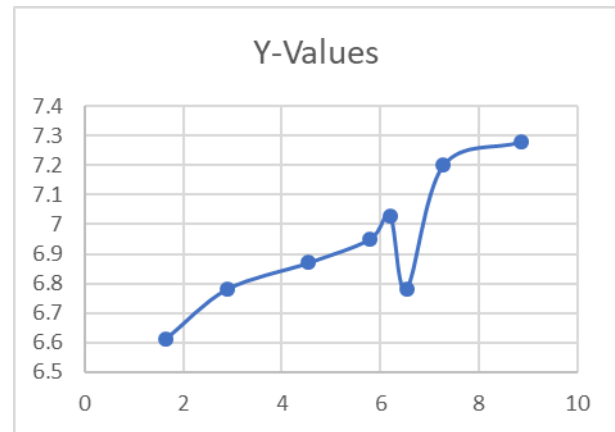


Fig 12.  $I_{DS}$  vs  $V_{DS}$  for BJT at -14 degrees

**III. When BJT temperature 40 degrees**

$V_{DS}$ in v	$I_{DS}$ in mA
1.64	6.61
2.89	6.78
4.54	6.87
5.79	6.95
6.20	7.03
6.53	6.78
7.28	7.20
8.85	7.28

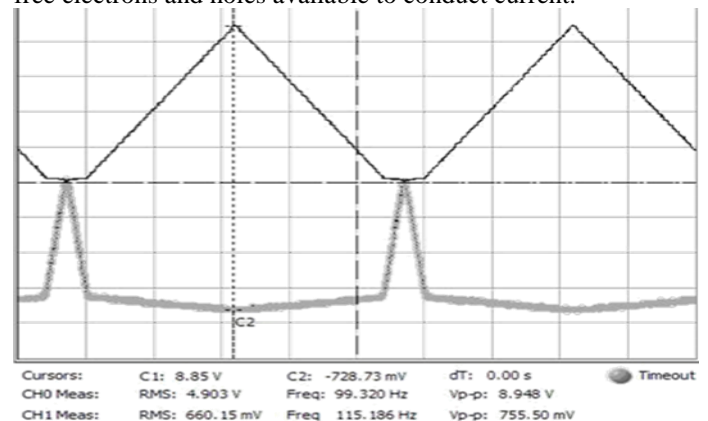


**Fig13.  $I_{DS}$  vs  $D_{DS}$  for BJT at 40 degrees**

**IV.** As it can be seen from tables 15, 16 and 17 and graphs in figure 10, 12 and 13, as we increase the temperature, the current for a certain drain voltage increases, as we decrease the temperature, the current decreases. So the temperature has a strong effect on the operations of the BJT transistor. Everything comes back to the physics of the components. As the temperature increases, there are more free holes and electrons to carry the charges, as a result the  $I_{DS}$   $V_{DS}$  curve shifts up as we increase the temperature.

As was explained earlier, from theory, we know that the BJT's behavior changes with temperature, as temperature increases the I-V curve shifts to the left, so the barrier voltage is lowered and when the temperature is decreased, the curve shift to the right, which means the barrier voltage is increased. This follows from the fact that as the temperature increases, we have more thermally generated holes and free electrons, this will decrease the voltage barrier at the PN junction. Which causes the BJT to conduct more current at lower voltages!

By comparing the three graphs, we see that for 22 degrees and 40 degrees the values and the graph are very similar, while for -14 degrees, for a given value of  $V_{DS}$ ,  $I_{DS}$  is smaller. That is explained by the fact that at lower temperatures, there are less free electrons and holes available to conduct current.



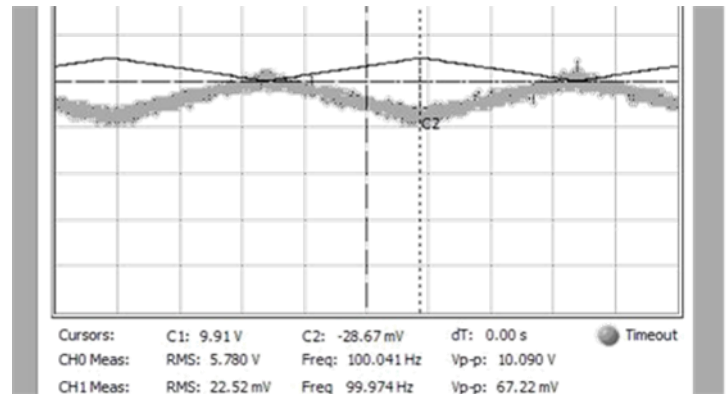
**BJT  $V_{DS}$  Vs  $Y_y$  when at 60 degrees**

## CONCLUSION

To conclude, this lab was very helpful and eye opening because various circuits were built using MOSFETs and BJTs, and their behavior were observed under different conditions and in different circuits, and this created a contrast with everything learnt in the classroom. We saw in this lab that a MOSFETs and BJTs are heavily influenced by temperature, and we saw that for different values of  $V_{ds}$ , the transistors behave differently. When  $V_{ds}$  is less than  $V_{gs} - V_{th}$ , then the MOSFET functions in the triode region, if  $V_{ds}$  is more than the overdrive voltage, then it is saturated and the current  $I_{ds}$  is thus saturated.

We saw how the I-V characteristic curve of the diode changes as the temperature changes, theory predicted that as the temperature increased, the diode I-V curve would shift left by 2mV and if the temperature decreased, it would shift to the right by 2mV. Experimental data showed that it does shift to the left when temperature increases, and that the I-V curve shifts to the right when temperature decreases, but it did not shift to the left and right by exactly 2mV, it was more pronounced.

In this lab, the experiments overall confirmed what was learned in class, various circuits were built and the usefulness of the MOSFET and BJT transistors were demonstrated.



**BJT  $V_{ds}$  Vs  $V_y$  when at -14 degrees**